Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/648,944	LAIL ET AL.	
Examiner	Art Unit	
Sanh D. Phu	2618	

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST	9/5/06	Zp		